

RELIABILITY DATA LT2940 / LT4275

9/21/2012

• OPERATING LIFE TEST

| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE HOURS ⁽¹⁾ T +125°C | NUMBER OF ⁽²⁾ FAILURES |
|---------------|-------------|------------------|------------------|---|--------------------------------------|
| SOIC/SOT/MSOP | 77 77 | 1025 | 1025 | 77.00 77.00 | 0 0 |

• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH⁽⁵⁾

| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE HOURS ⁽⁴⁾ AT +85°C | NUMBER OF FAILURES |
|---------------|-------------|------------------|------------------|---|-----------------------|
| SOIC/SOT/MSOP | 214 214 | 0927 | 1010 | 571.04 571.04 | 0 0 |

• PRESSURE COOKER TEST AT 15 PSIG, +121°C⁽⁵⁾

| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE HOURS | NUMBER OF FAILURES |
|---------------|------------------|------------------|------------------|--------------------------|-----------------------|
| SOIC/SOT/MSOP | 25,978 25,978 | 0640 | 0827 | 102,744.00 102,744.00 | 0 0 |

• TEMP CYCLE FROM -65°C to +150°C⁽⁵⁾

| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE CYCLES | NUMBER OF FAILURES |
|---------------|------------------|------------------|------------------|----------------------|-----------------------|
| SOIC/SOT/MSOP | 19,455 19,455 | 0507 | 1024 | 4,712.74 4,712.74 | 0 0 |

• THERMAL SHOCK FROM -65°C to +150°C⁽⁵⁾

| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE CYCLES | NUMBER OF FAILURES |
|---------------|------------------|------------------|------------------|----------------------|-----------------------|
| SOIC/SOT/MSOP | 20,997 20,997 | 0507 | 1033 | 5,596.39 5,596.39 | 0 0 |

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 23.74 FITS

(3) Mean Time Between Failures in Years = 4,808

(4) Assumes 20x acceleration from 85°C to 131°C

(5) Environmental stress data given by Process, Package Technology similarity

Note: 1 FIT = 1 Failure in One Billion Hours.